

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination MIYOSHI, KENICHI	
			Examiner Hai V. Nguyen	Art Unit 2618	Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,504,775 A	04-1996	Chouly et al.	370/210
*	B	US-5,659,882 A	08-1997	Fukutomi, Rejiro	455/524
*	C	US-2002/0137464 A1	09-2002	Dolgonos et al.	455/60
*	D	US-2002/0160765 A1	10-2002	Okajima, Ichiro	455/419
*	E	US-2002/0183083 A1	12-2002	Nagira et al.	455/503
*	F	US-2003/0032420 A1	02-2003	KUHN et al.	455/420
*	G	US-2003/0109285 A1	06-2003	Reed et al.	455/562
*	H	US-2003/0125067 A1	07-2003	Takeda et al.	455/522
*	I	US-2003/0165127 A1	09-2003	Fujiwara et al.	370/335
*	J	US-6,640,087 B2	10-2003	Reed et al.	455/11.1
*	K	US-2004/0023652 A1	02-2004	Shah et al.	455/426.2
*	L	US-2004/0114618 A1	06-2004	Tong et al.	370/431
*	M	US-2004/0131025 A1	07-2004	Dohler et al.	370/328

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/591,707	MIYOSHI, KENICHI	
	Examiner Hai V. Nguyen	Art Unit 2618	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0203941 A1	10-2004	Kaplan et al.	455/466
*	B	US-2005/0014464 A1	01-2005	Larsson, Peter	455/011.1
*	C	US-2005/0025042 A1	02-2005	Hadad, Zion	370/208
*	D	US-2005/0059342 A1	03-2005	Engels et al.	455/007
*	E	US-2005/0113022 A1	05-2005	Pearson, Ian D	455/011.1
*	F	US-2005/0141593 A1	06-2005	Pasanen et al.	375/130
*	G	US-2005/0190821 A1	09-2005	Fujii et al.	375/211
*	H	US-2006/0084475 A1	04-2006	Ohkubo et al.	455/562.1
*	I	US-7,031,293 B1	04-2006	Srikrishna et al.	370/348
*	J	US-2006/0209671 A1	09-2006	Khan et al.	370/208
*	K	US-2006/0229017 A1	10-2006	Larsson et al.	455/063.1
*	L	US-2002/0127968	09-2002	Takemoto et al.	455/24
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.